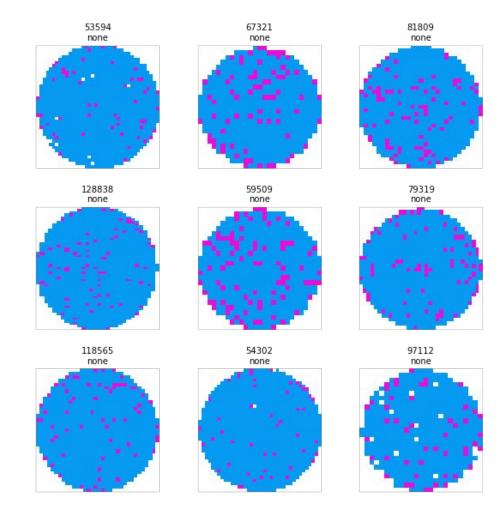
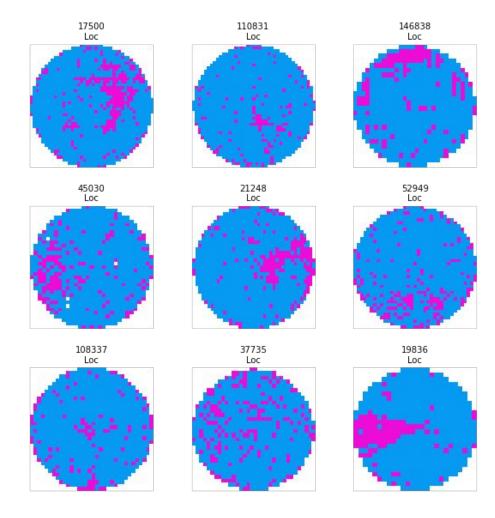
Failure Type Visualization

9 random examples of each wafer map failure type from train/dev datasets, resized to 224x224

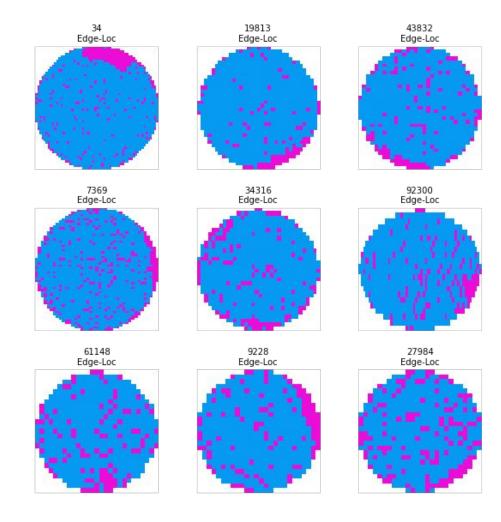
None



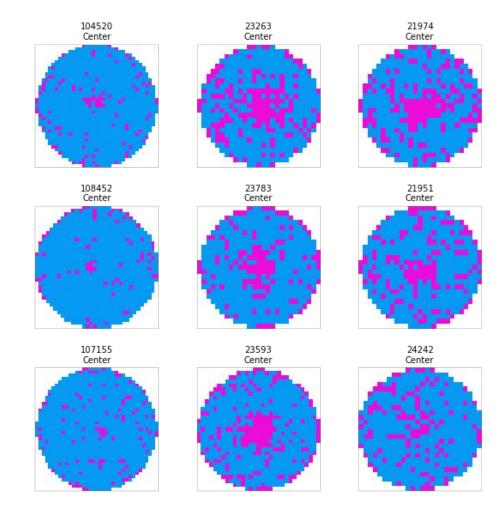
Loc



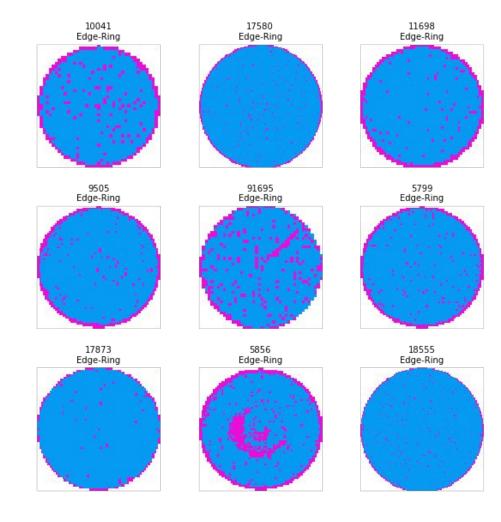
Edge Loc



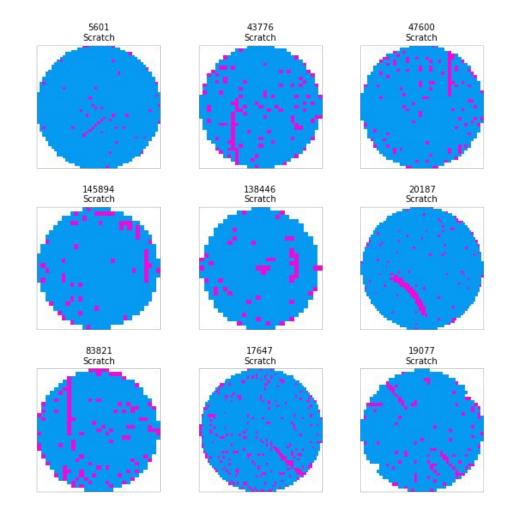
Center



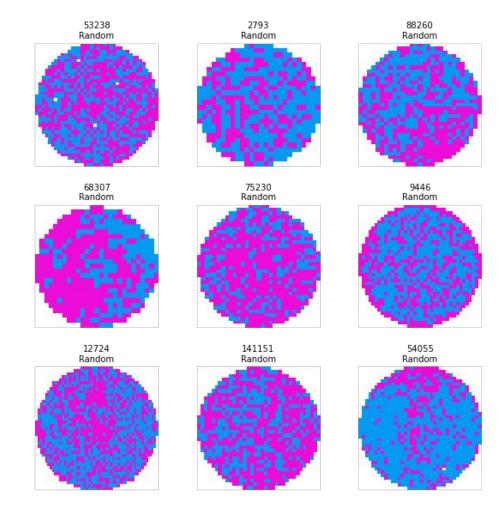
Edge Ring



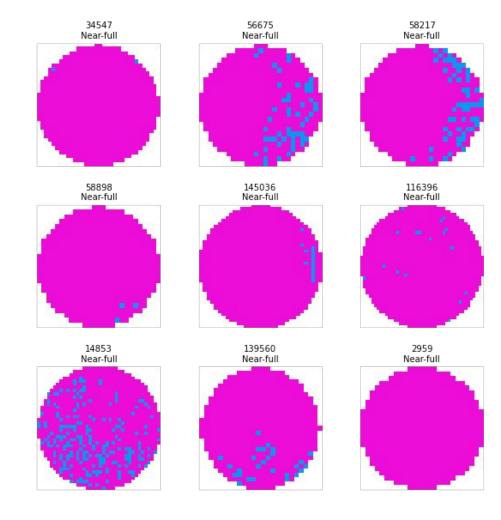
Scratch



Random



Near Full



Donut

